



# STU/D802S

SamHop Microelectronics Corp.

Ver 1.0

## N-Channel Logic Level Enhancement Mode Field Effect Transistor

PRODUCT SUMMARY		
VDSS	ID	RDS(ON) (mΩ) Max
80V	25A	35 @ VGS=10V
		50 @ VGS=4.5V

### FEATURES

- Super high dense cell design for low RDS(ON).
- Rugged and reliable.
- TO-252 and TO-251 Package.

<b>ABSOLUTE MAXIMUM RATINGS (T<sub>C</sub>=25°C unless otherwise noted)</b>		
Symbol	Parameter	Limit
V <sub>DS</sub>	Drain-Source Voltage	80
V <sub>GS</sub>	Gate-Source Voltage	±20
I <sub>D</sub>	Drain Current-Continuous <sup>a</sup>	25
I <sub>DM</sub>	-Pulsed <sup>b</sup>	100
E <sub>AS</sub>	Avalanche Energy <sup>c</sup>	196
P <sub>D</sub>	Maximum Power Dissipation <sup>a</sup>	62.5
T <sub>J</sub> , T <sub>STG</sub>	Operating Junction and Storage Temperature Range	-55 to 150

### THERMAL CHARACTERISTICS

R <sub>θJC</sub>	Thermal Resistance, Junction-to-Case	2	°C/W
R <sub>θJA</sub>	Thermal Resistance, Junction-to-Ambient	50	°C/W

Mar,31,2010

# STU/D802S

Ver 1.0

## ELECTRICAL CHARACTERISTICS ( $T_c=25^\circ\text{C}$ unless otherwise noted)

Symbol	Parameter	Conditions	Min	Typ	Max	Units
<b>OFF CHARACTERISTICS</b>						
$\text{BV}_{\text{DSS}}$	Drain-Source Breakdown Voltage	$\text{V}_{\text{GS}}=0\text{V}$ , $\text{I}_D=250\mu\text{A}$	80			V
$\text{I}_{\text{DSS}}$	Zero Gate Voltage Drain Current	$\text{V}_{\text{DS}}=64\text{V}$ , $\text{V}_{\text{GS}}=0\text{V}$			1	A
$\text{I}_{\text{GSS}}$	Gate-Body leakage current	$\text{V}_{\text{GS}}= \pm 20\text{V}$ , $\text{V}_{\text{DS}}=0\text{V}$			$\pm 100$	$\text{nA}$
<b>ON CHARACTERISTICS</b>						
$\text{V}_{\text{GS}(\text{th})}$	Gate Threshold Voltage	$\text{V}_{\text{DS}}=\text{V}_{\text{GS}}$ , $\text{I}_D=250\mu\text{A}$	1		3	V
$\text{R}_{\text{DS}(\text{ON})}$	Drain-Source On-State Resistance	$\text{V}_{\text{GS}}=10\text{V}$ , $\text{I}_D=16\text{A}$		25	35	m ohm
		$\text{V}_{\text{GS}}=4.5\text{V}$ , $\text{I}_D=14\text{A}$		32	50	m ohm
$\text{g}_{\text{FS}}$	Forward Transconductance	$\text{V}_{\text{DS}}=10\text{V}$ , $\text{I}_D=16\text{A}$		38		S
<b>DYNAMIC CHARACTERISTICS <sup>b</sup></b>						
$\text{C}_{\text{iss}}$	Input Capacitance	$\text{V}_{\text{DS}}=25\text{V}, \text{V}_{\text{GS}}=0\text{V}$ $f=1.0\text{MHz}$		3270		pF
$\text{C}_{\text{oss}}$	Output Capacitance			210		pF
$\text{C}_{\text{rss}}$	Reverse Transfer Capacitance			145		pF
<b>SWITCHING CHARACTERISTICS <sup>b</sup></b>						
$t_{\text{D}(\text{ON})}$	Turn-On DelayTime	$\text{V}_{\text{DD}}=40\text{V}$ $\text{I}_D=16\text{A}$ $\text{V}_{\text{GS}}=10\text{V}$ $\text{R}_{\text{GEN}}=60\text{ ohm}$		66		ns
$t_r$	Rise Time			166		ns
$t_{\text{D}(\text{OFF})}$	Turn-Off DelayTime			222		ns
$t_f$	Fall Time			55		ns
$Q_g$	Total Gate Charge	$\text{V}_{\text{DS}}=64\text{V}, \text{I}_D=16\text{A}, \text{V}_{\text{GS}}=10\text{V}$		50		nC
$Q_{\text{gs}}$	Gate-Source Charge	$\text{V}_{\text{DS}}=64\text{V}, \text{I}_D=16\text{A},$ $\text{V}_{\text{GS}}=10\text{V}$		6		nC
$Q_{\text{gd}}$	Gate-Drain Charge			16		nC
<b>DRAIN-SOURCE DIODE CHARACTERISTICS AND MAXIMUM RATINGS</b>						
$I_s$	Maximum Continuous Drain-Source Diode Forward Current				16	A
$\text{V}_{\text{SD}}$	Diode Forward Voltage	$\text{V}_{\text{GS}}=0\text{V}, \text{I}_s=16\text{A}$		0.9	1.3	V

### Notes

- a.Pulse Test:Pulse Width  $\leq 300\mu\text{s}$ , Duty Ctcle  $\leq 2\%$ .
- b.Guaranteed by design, not subject to production testing.
- c.Starting  $\text{T}_j=25^\circ\text{C}$ , $L=0.5\text{mH}$ , $\text{V}_{\text{DD}} = 40\text{V}$ .(See Figure13)

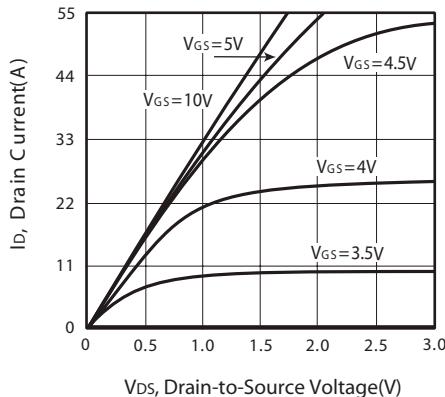


Figure 1. Output Characteristics

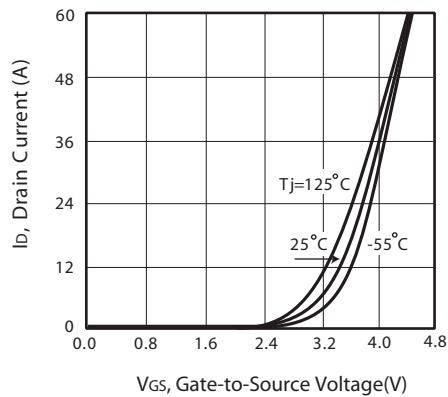


Figure 2. Transfer Characteristics

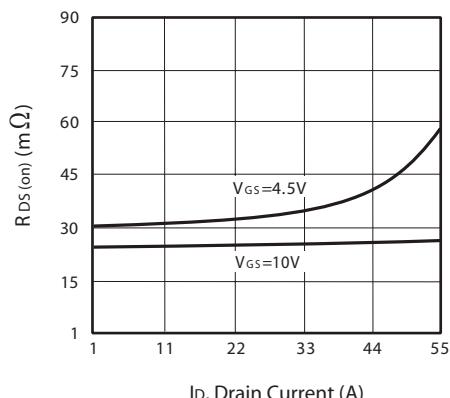


Figure 3. On-Resistance vs. Drain Current and Gate Voltage

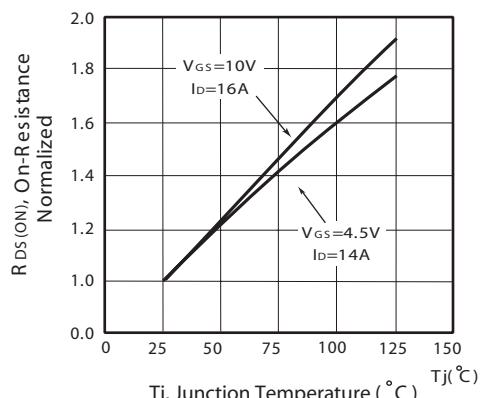


Figure 4. On-Resistance Variation with Drain Current and Temperature

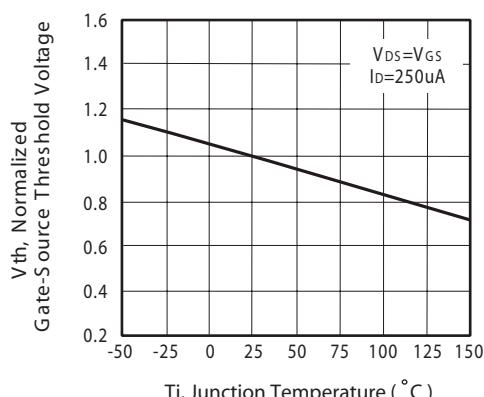


Figure 5. Gate Threshold Variation with Temperature

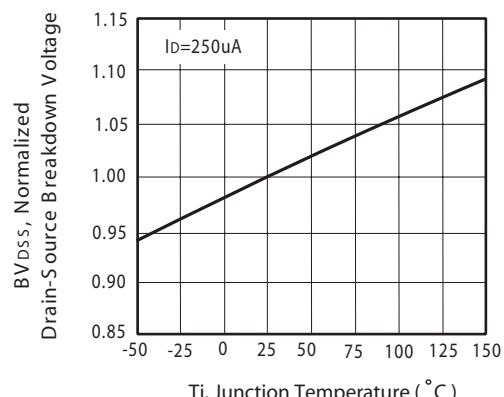


Figure 6. Breakdown Voltage Variation with Temperature

# STU/D802S

Ver 1.0

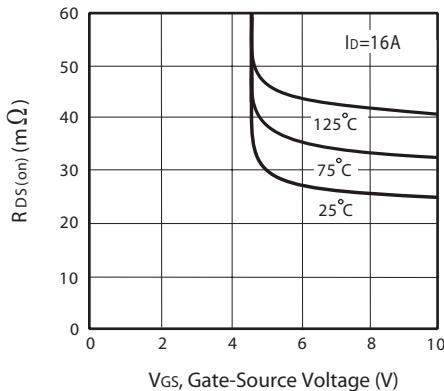


Figure 7. On-Resistance vs. Gate-Source Voltage

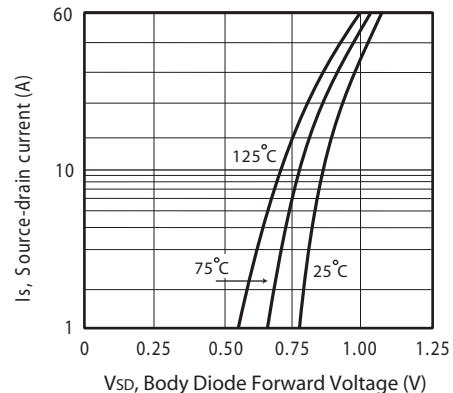


Figure 8. Body Diode Forward Voltage Variation with Source Current

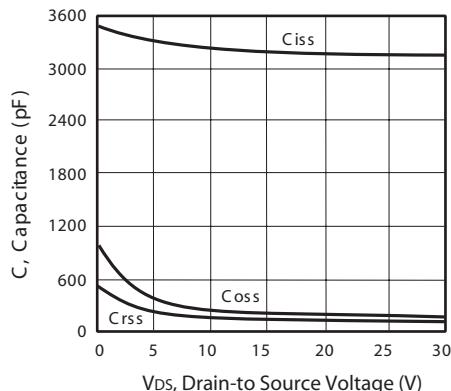


Figure 9. Capacitance

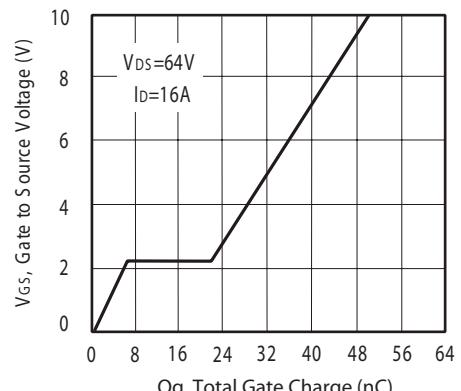


Figure 10. Gate Charge

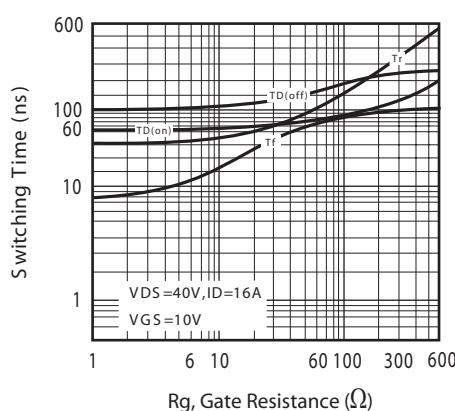


Figure 11. Switching Characteristics

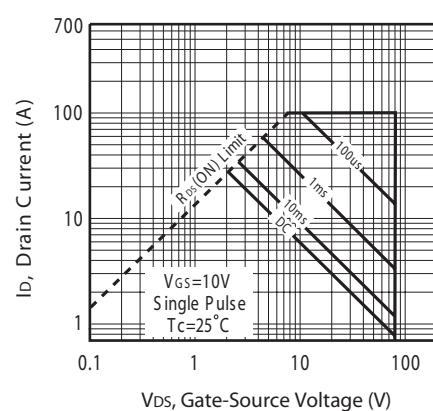
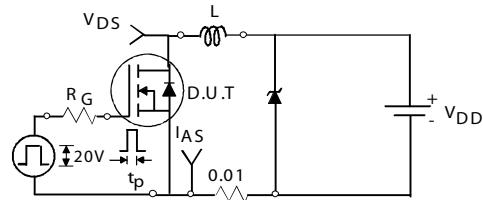


Figure 12. Maximum Safe Operating Area

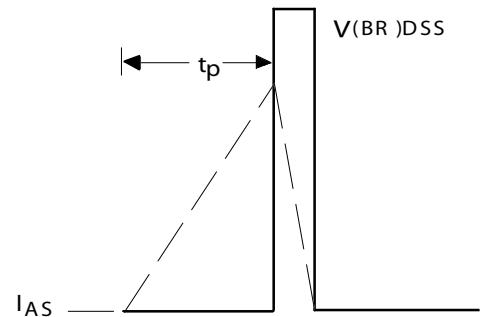
# STU/D802S

Ver 1.0



Unclamped Inductive Test Circuit

Figure 13a.



Unclamped Inductive Waveforms

Figure 13b.

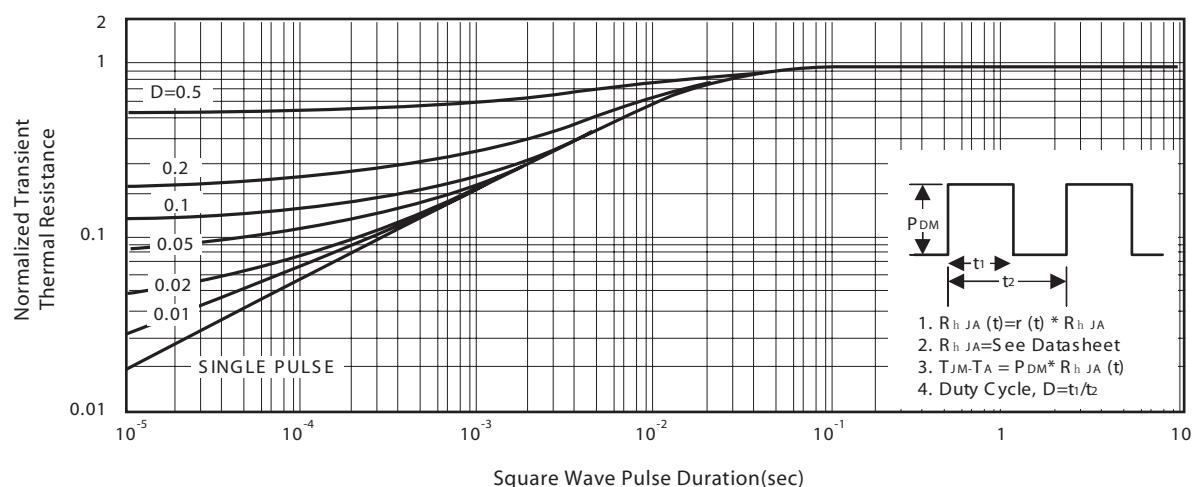


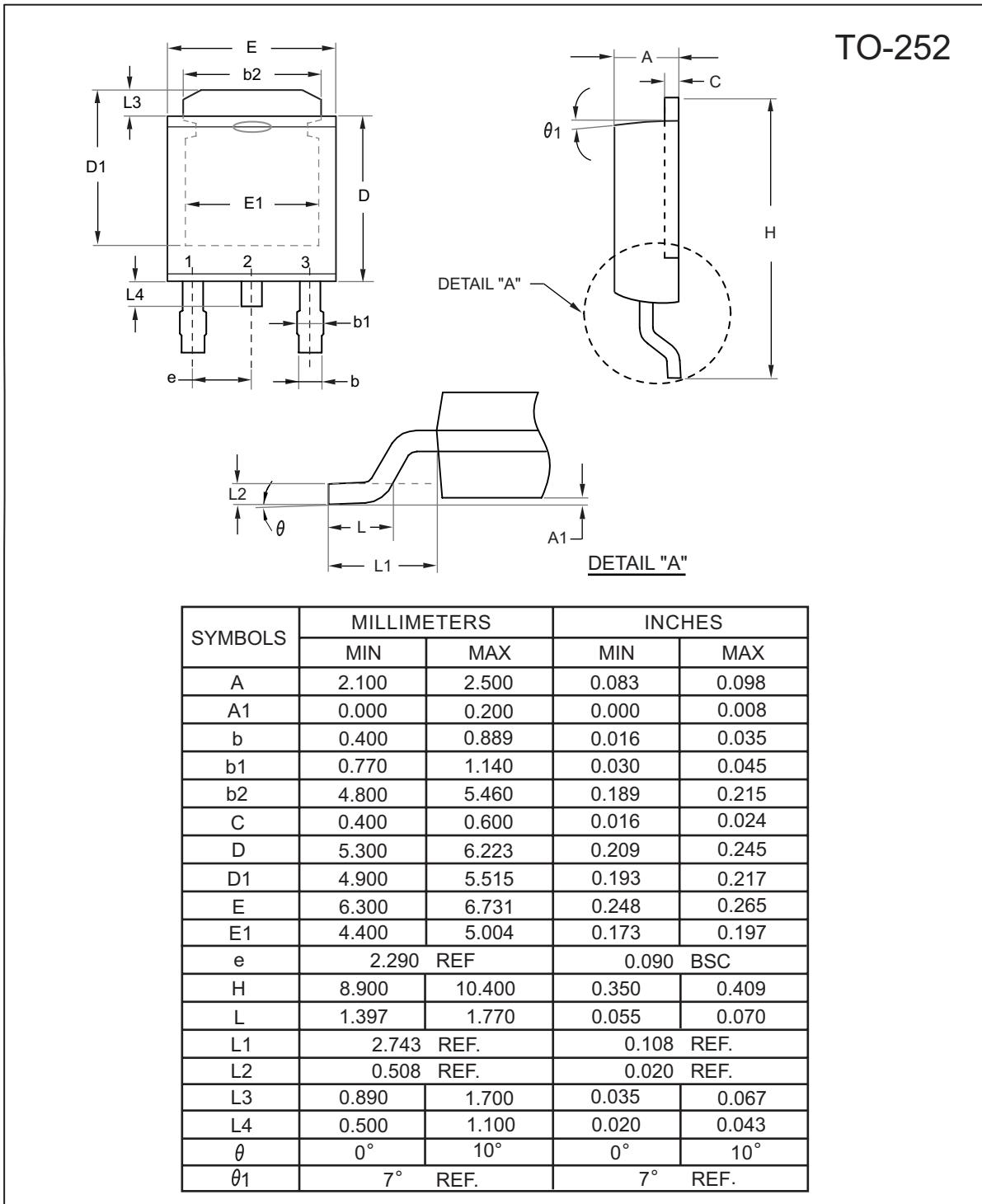
Figure 14. Normalized Thermal Transient Impedance Curve

## PACKAGE OUTLINE DIMENSIONS

TO-251		MILLIMETERS		INCHES	
SYMBOL		MIN	MAX	MIN	MAX
A		2.100	2.500	0.083	0.098
A1		0.350	0.650	0.014	0.026
B		0.400	0.800	0.016	0.031
B1		0.650	1.050	0.026	0.041
B2		0.500	0.900	0.020	0.035
C		0.400	0.600	0.016	0.024
D		5.300	5.700	0.209	0.224
D1		4.900	5.300	0.193	0.209
D2		6.700	7.300	0.264	0.287
D3		7.000	8.000	0.276	0.315
H		13.700	15.300	0.539	0.602
E		6.300	6.700	0.248	0.264
E1		4.600	4.900	0.181	0.193
E2		4.800	5.200	0.189	0.205
L		1.300	1.700	0.051	0.067
L1		1.400	1.800	0.055	0.071
L2		0.500	0.900	0.020	0.035
P		2.300 BSC		0.091 BSC	

# STU/D802S

Ver 1.0



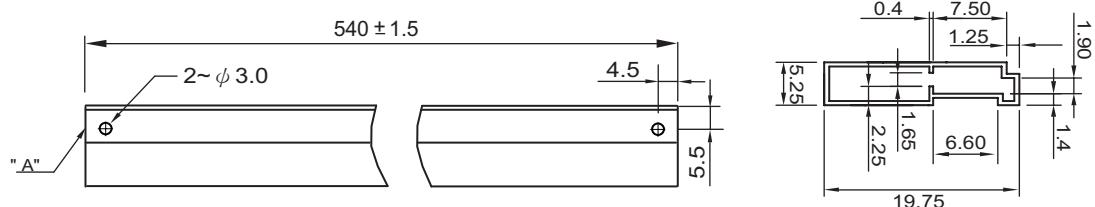
Mar,31,2010

# STU/D802S

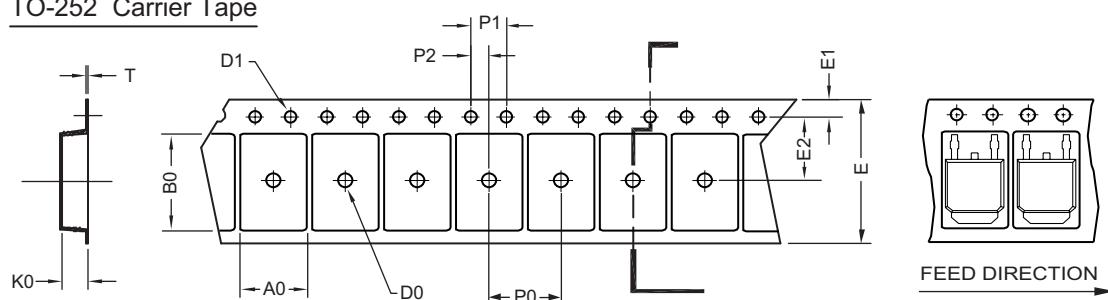
Ver 1.0

TO-251 Tube

## TO251 Tube/TO-252 Tape and Reel Data



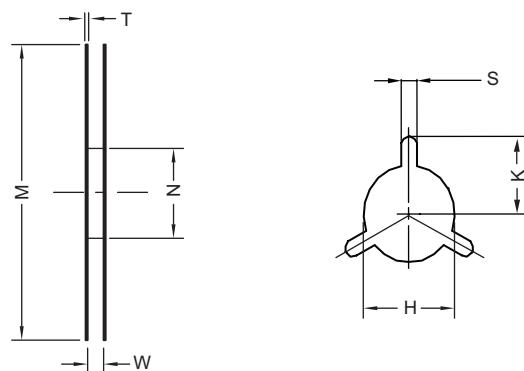
TO-252 Carrier Tape



UNIT:mm

PACKAGE	A0	B0	K0	D0	D1	E	E1	E2	P0	P1	P2	T
TO-252 (16 mm)	6.96 ±0.1	10.49 ±0.1	2.79 ±0.1	ψ 2	ψ 1.5 + 0.1 - 0	16.0 ±0.3	1.75 ±0.1	7.5 ±0.15	8.0 ±0.1	4.0 ±0.1	2.0 ±0.15	0.3 ±0.05

TO-252 Reel



UNIT:mm

TAPE SIZE	REEL SIZE	M	N	W	T	H	K	S	G	R	V
16 mm	ψ 330	ψ 330 ± 0.5	ψ 97 ± 1.0	17.0 + 1.5 - 0	2.2	ψ 13.0 + 0.5 - 0.2	10.6	2.0 ± 0.5	---	---	---

Mar,31,2010